

Notice of References Cited	Application/Control No. 09/921,293		Applicant(s)/Patent Under Reexamination CLARKE ET AL.	
	Examiner Jeffrey R. West		Art Unit 2857	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,751,979	08-1973	Ims, John Robert	73/861.27
*	B	US-4,463,612	08-1984	Thompson, William L.	73/861.22
*	C	US-5,493,915	02-1996	Lew et al.	73/861.24
*	D	US-5,576,497	11-1996	Vignos et al.	73/861.22
*	E	US-6,298,100	10-2001	Bouillet, Aaron Reel	375/326
*	F	US-5,570,300	10-1996	Henry et al.	702/45
*	G	US-4,201,084	05-1980	Ito et al.	73/861.22
*	H	US-5,128,625	07-1992	Yatsuzuka et al.	327/156
*	I	US-2001/0008384	07-2001	Ku, Do-Il	331/2
*	J	US-5,502,711	03-1996	Clark et al.	369/59.17
*	K	US-5,414,390	05-1995	Kovacs et al.	331/2
*	L	US-6,438,177	08-2002	Ikeda, Hitoshi	375/316
*	M	US-5,152,005	09-1992	Bickley, Robert H.	455/76

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	William F. Egan, "Chapter 9: Acquisition Aids," Phase-Lock Basics, John Wiley & Sons, Inc., 1998, pp. 209-210 and 222-227.
*	V	"General Metrology --- Part 3: Guide to the Expression of Uncertainty in Measurement (GUM)," Published Document PD 6461-3:1995, British Standards, January 15, 1995, pp. 1-105.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	Examiner Jeffrey R. West	Art Unit 2857	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,072,195	12-1991	Graham et al.	331/2
*	B	US-4,019,153	04-1977	Cox et al.	331/1A
*	C	US-5,029,004	07-1991	Shibayama, Kenji	348/625
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N					
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	R					
	S					
	T					

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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